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(12) **United States Design Patent**
Iwata et al.

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(54) **RESIDUAL STRESS MEASURING DEVICE**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

Dec. 22, 2015 (JP) 2015-028447

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/83**

(58) **Field of Classification Search**
USPC D10/83-85
CPC B24C 1/10; B24C 3/00; B24C 3/04; G01N 23/207; G01N 2203/008
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D400,456 S * 11/1998 Inoue D10/85
D456,290 S * 4/2002 Gunji D10/85

D630,957 S * 1/2011 Hsieh D10/83
D701,131 S * 3/2014 Kurisaki D10/85
D709,393 S * 7/2014 Lee D10/83
D737,161 S * 8/2015 Okazaki D10/83
D750,783 S * 3/2016 Yasukawa D24/158
D781,734 S * 3/2017 Lim D10/83

* cited by examiner

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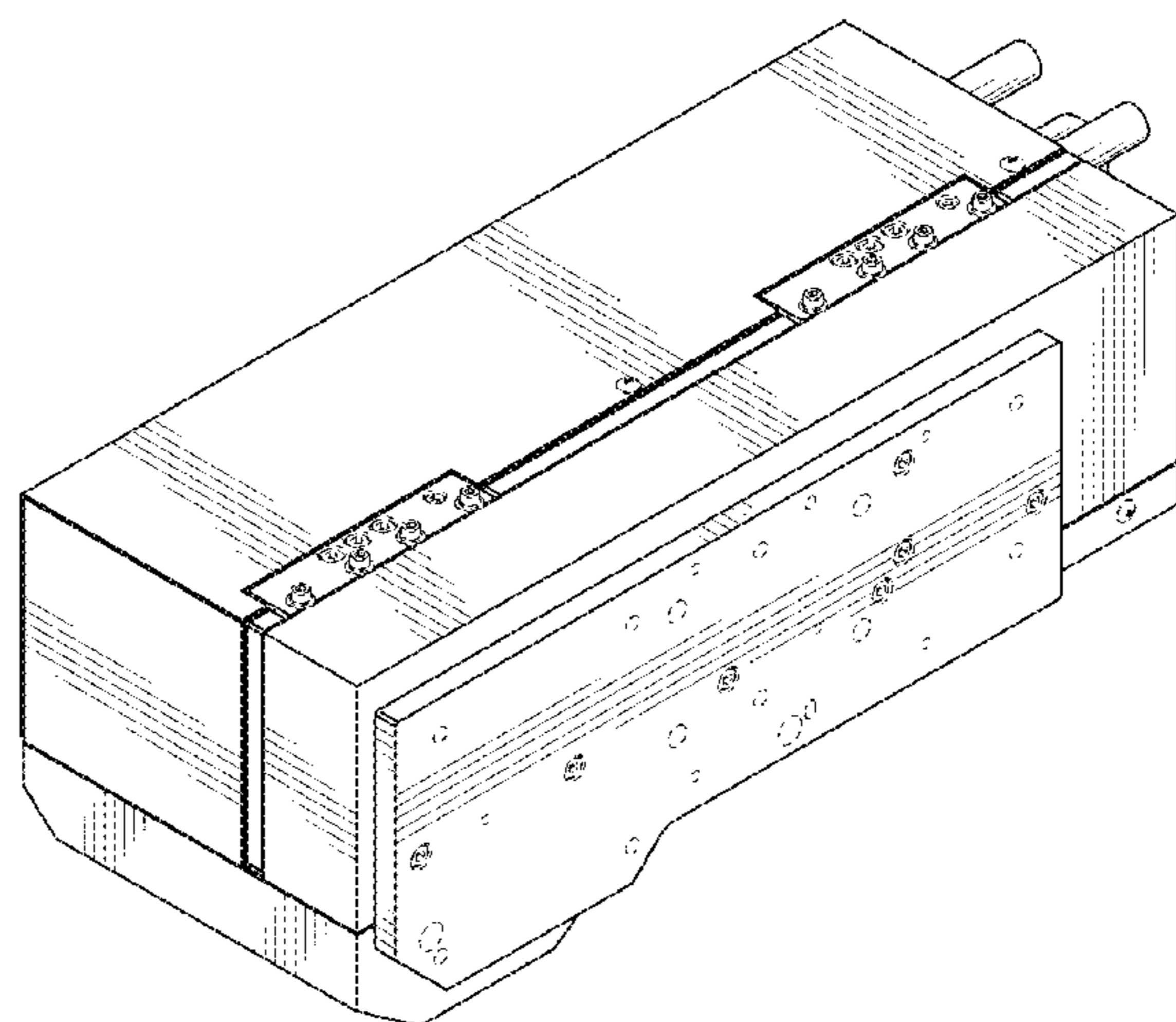
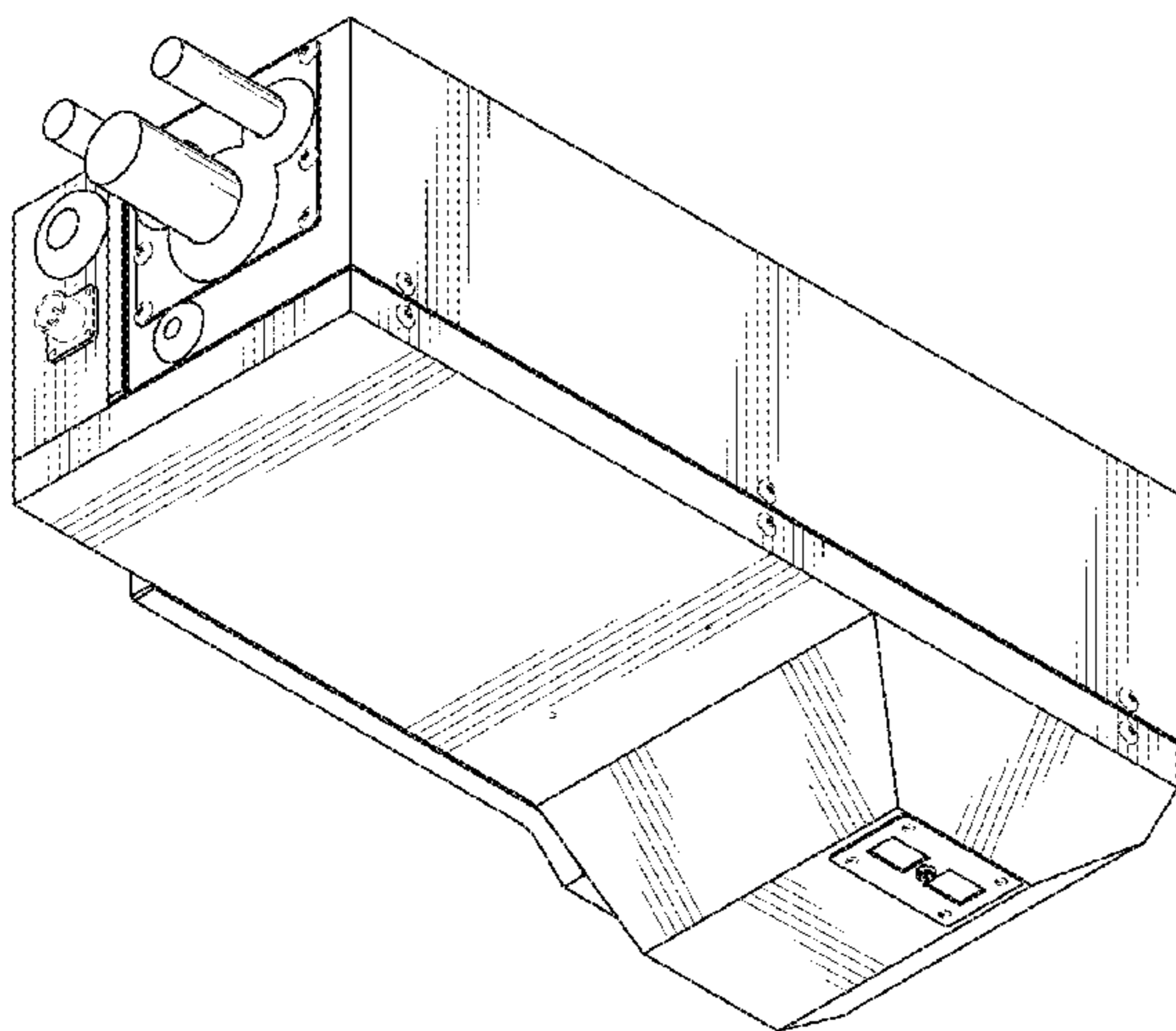
(57) **CLAIM**

The ornamental design for a residual stress measuring device, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of a residual stress measuring device showing our new design; FIG. 2 is a rear elevational view thereof; FIG. 3 is a left side elevational view thereof; FIG. 4 is a right side elevational view thereof; FIG. 5 is a top plan view thereof; FIG. 6 is a bottom plan view thereof; FIG. 7 is a front, bottom, left side perspective view thereof; and, FIG. 8 is a rear, top, right side perspective view thereof. The broken lines illustrate structure or features which form no part of the claimed design. The drawings include surface shading which represents contour and not surface ornamentation.

1 Claim, 4 Drawing Sheets



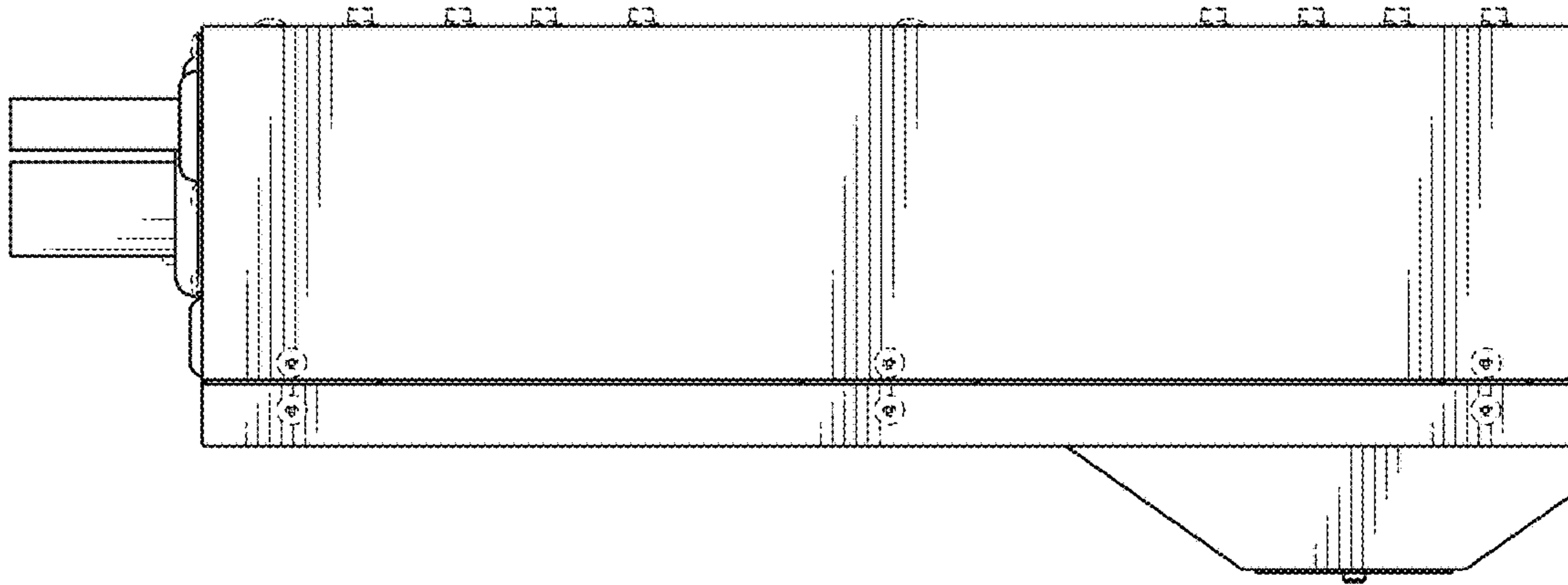


FIG. 1

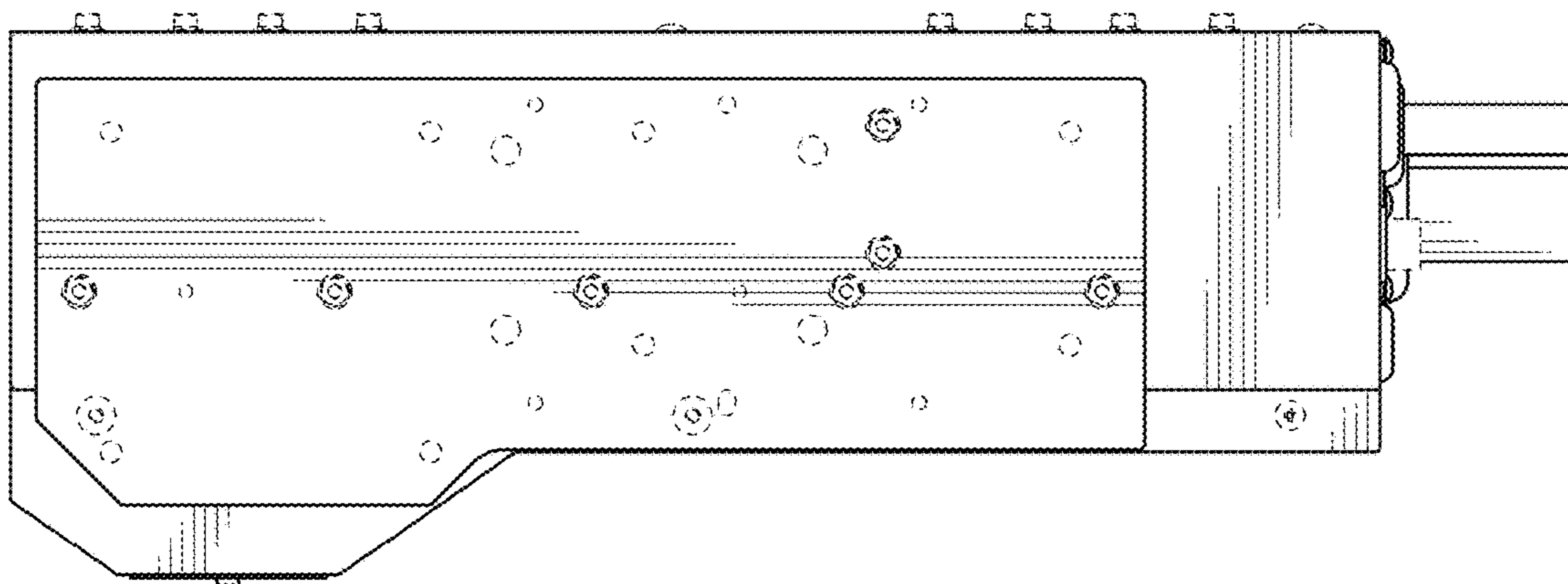


FIG. 2

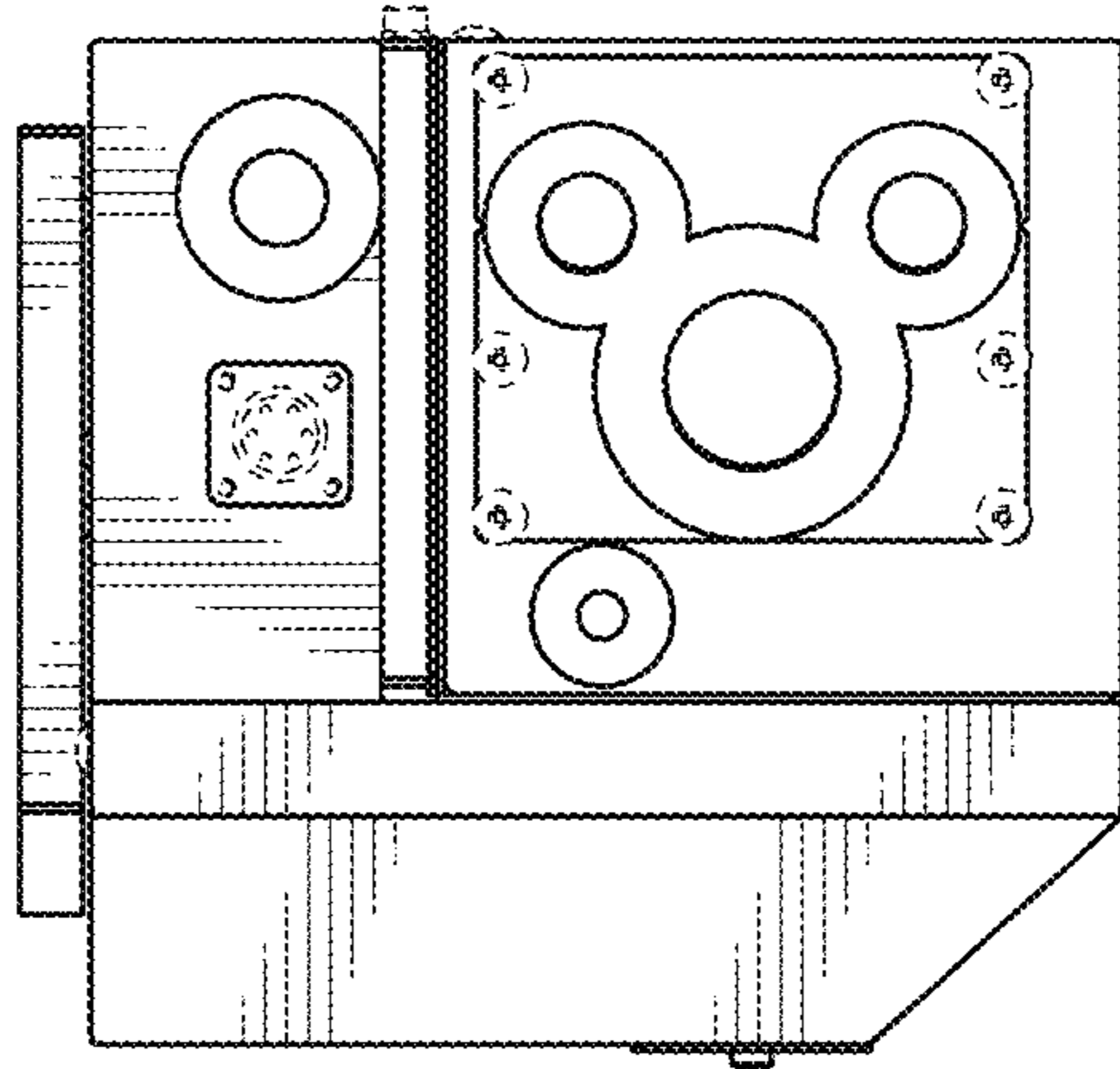


FIG. 3

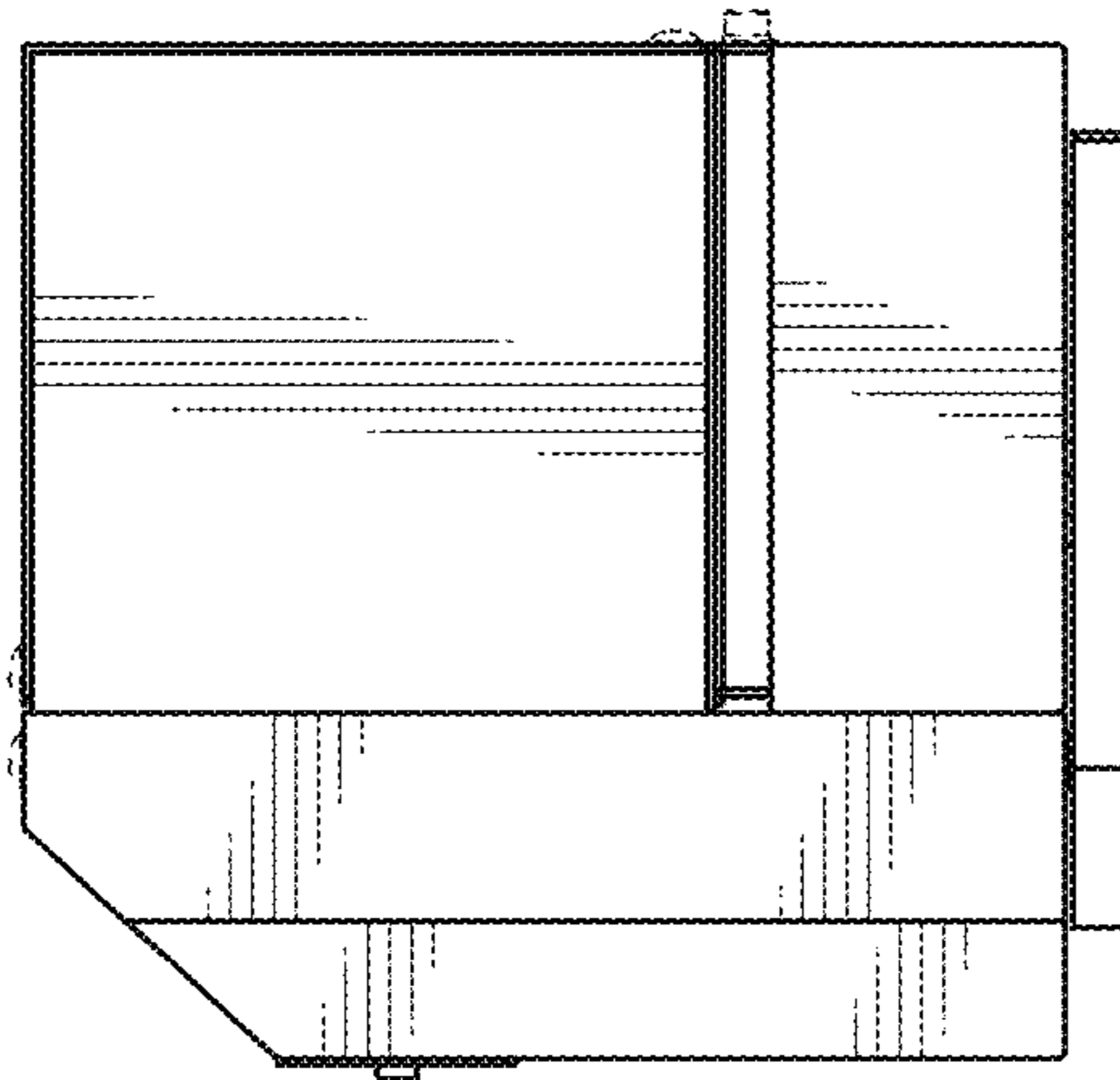


FIG. 4

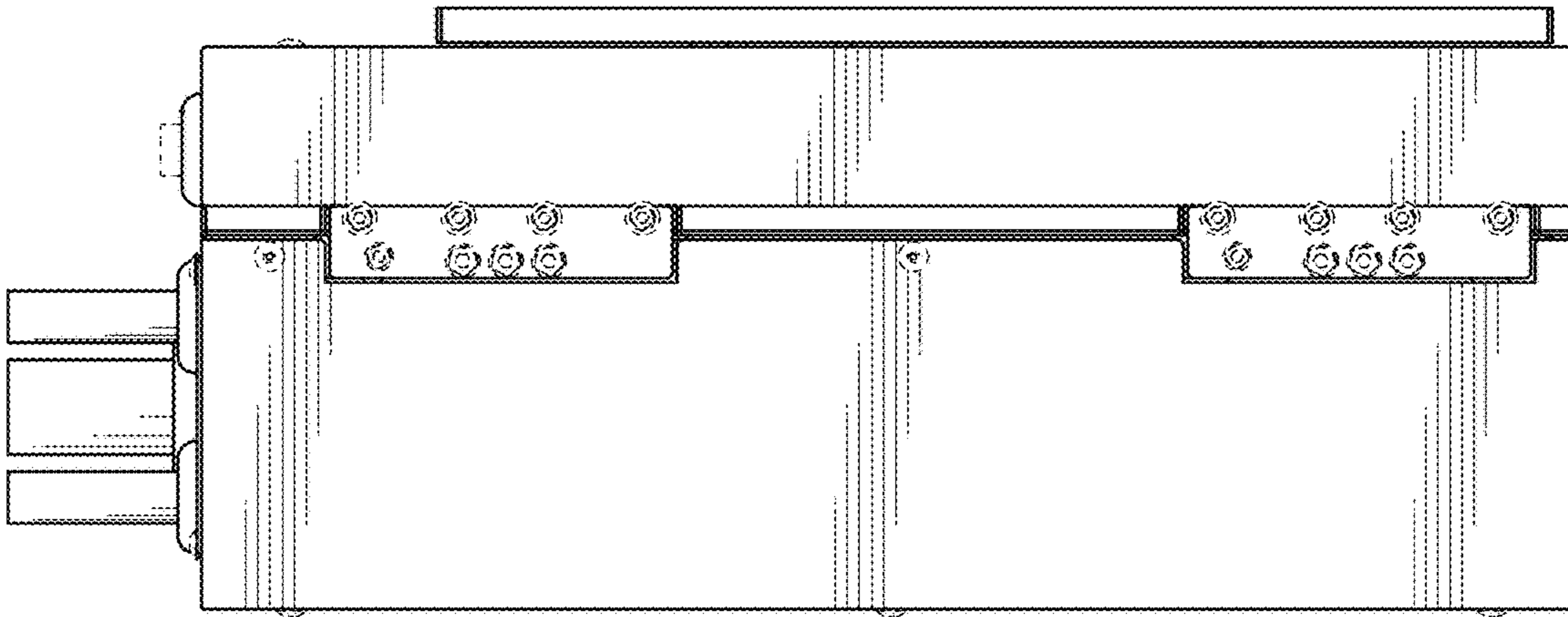


FIG. 5

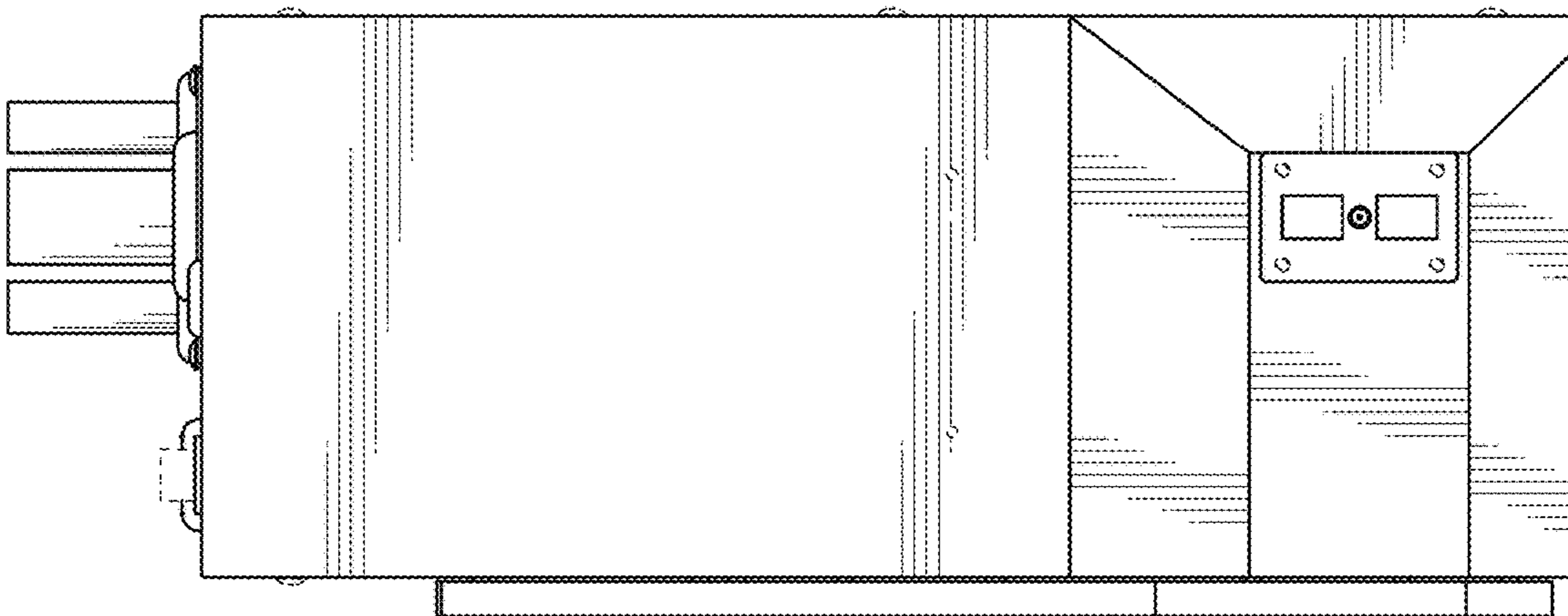


FIG. 6

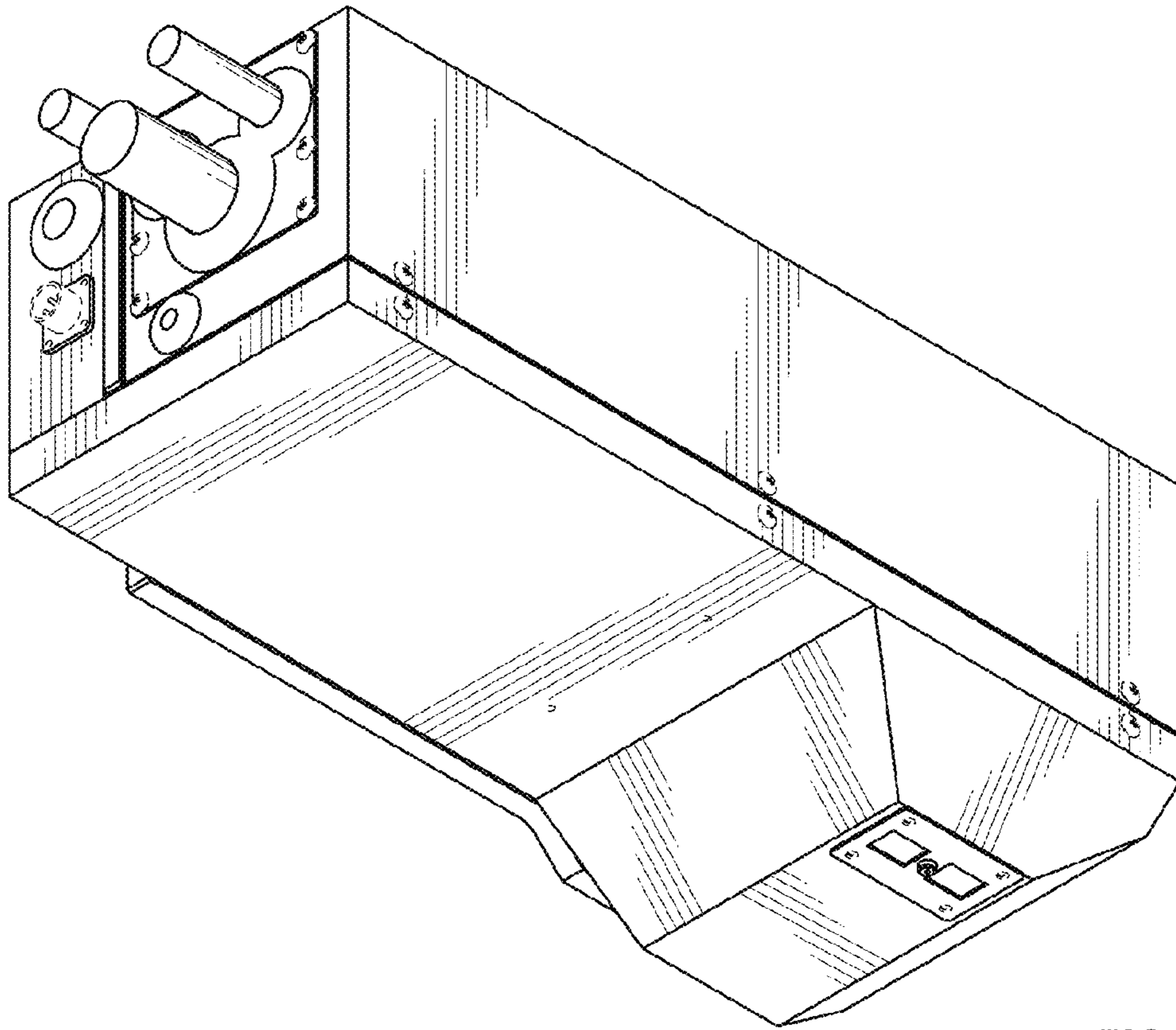


FIG. 7

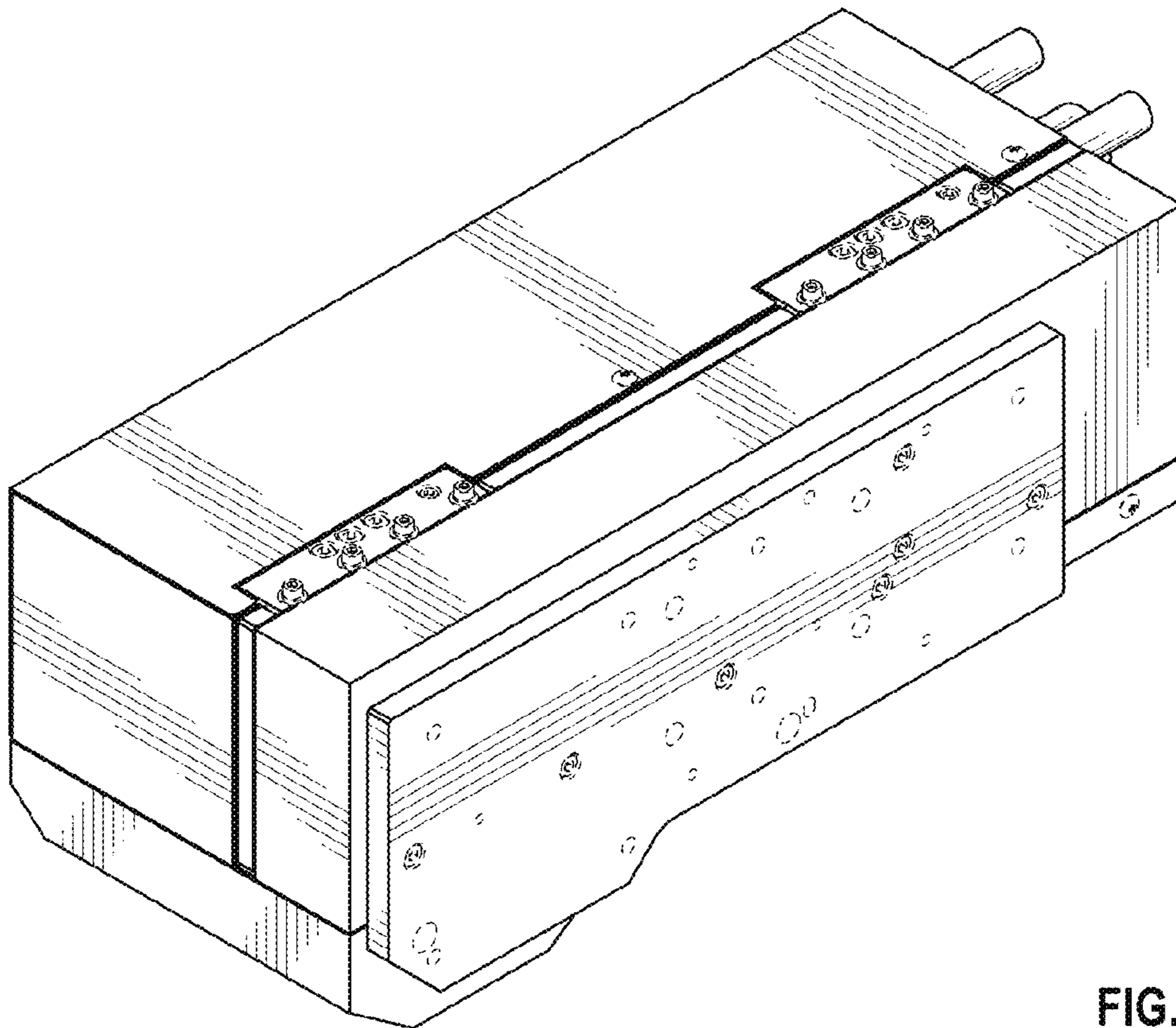


FIG. 8